

CD40106B Types

CMOS Hex Schmitt Triggers

High-Voltage Types (20-Volt Rating)

■ CD40106B consists of six Schmitt-trigger circuits. Each circuit functions as an inverter with Schmitt-trigger action on the input. The trigger switches at different points for positive- and negative-going signals. The difference between the positive-going voltage (V_P) and the negative-going voltage (V_N) is defined as hysteresis voltage (V_H) (see Fig.6). The CD40106B types are supplied in 14-lead hermetic dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic package (E suffix), and in chip form (H suffix).

Features:

- Schmitt-trigger action with no external components
- Hysteresis voltage (typ.) 0.9 V at $V_{DD} = 5$ V, 2.3 V at $V_{DD} = 10$ V, and 3.5 V at $V_{DD} = 15$ V
- Noise immunity greater than 50%
- No limit on input rise and fall times
- Standardized, symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μ A at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Low V_{DD} to V_{SS} current during slow input ramp
- 5-V, 10-V, and 15-V parametric ratings
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Applications:

- Wave and pulse shapers
- High-noise-environment systems
- Monostable multivibrators
- Astable multivibrators

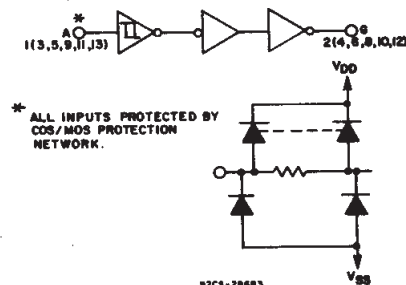
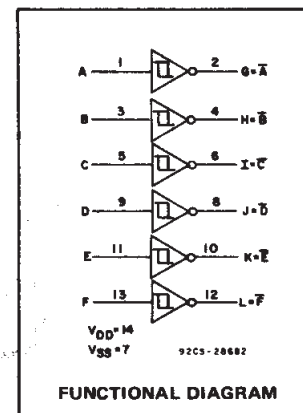


Fig.1 — Logic diagram
(1 of 6 Schmitt triggers).

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (V_{DD})

Voltages referenced to V_{SS} Terminal) -0.5V to +20V

INPUT VOLTAGE RANGE, ALL INPUTS -0.5V to $V_{DD} + 0.5$ V

DC INPUT CURRENT, ANY ONE INPUT ± 10 mA

POWER DISSIPATION PER PACKAGE (P_D):

For $T_A = -55^\circ\text{C}$ to $+100^\circ\text{C}$ 500 mW

For $T_A = +100^\circ\text{C}$ to $+125^\circ\text{C}$ Derate Linearity at 12 mW/ $^\circ\text{C}$ to 200 mW

DEVICE DISSIPATION PER OUTPUT TRANSISTOR

For $T_A = \text{FULL PACKAGE-TEMPERATURE RANGE (All Package Types)}$ 100 mW

OPERATING-TEMPERATURE RANGE (T_A) -55°C to $+125^\circ\text{C}$

STORAGE TEMPERATURE RANGE (T_{stg}) -65°C to $+150^\circ\text{C}$

LEAD TEMPERATURE (DURING SOLDERING):

At distance 1/16 $\pm$ 1/32 inch (1.59 $\pm$ 0.79 mm) from case for 10s max $+265^\circ\text{C}$

RECOMMENDED OPERATING CONDITIONS

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range (For T_A Full Package-Temperature Range)	3	18	V

DYNAMIC ELECTRICAL CHARACTERISTICS

At $T_A = 25^\circ\text{C}$, Input $t_r, t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω

CHARACTERISTIC	TEST CONDITIONS	LIMITS		UNITS	
		V _{DD} (V)	TYP.		MAX.
Propagation Delay Time:		5	140	280	ns
t _{PHL}		10	70	140	
t _{PLH}		15	60	120	
Transition Time:		5	100	200	ns
t _{THL}		10	50	100	
t _{TLH}		15	40	80	
Input Capacitance, C _{IN}	Any Input		5	7.5	pF

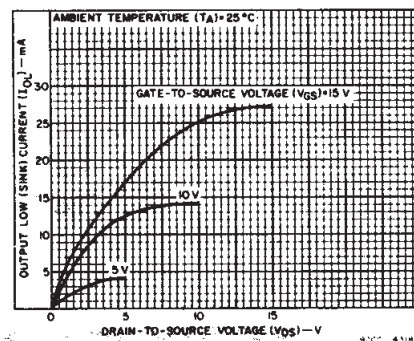


Fig.2 — Typical output low (sink)
current characteristics.

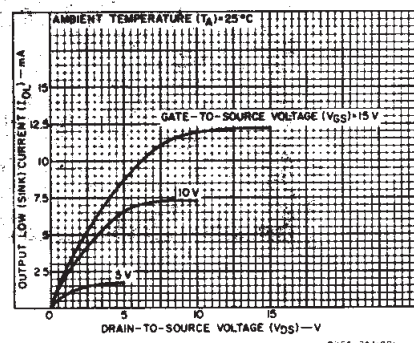
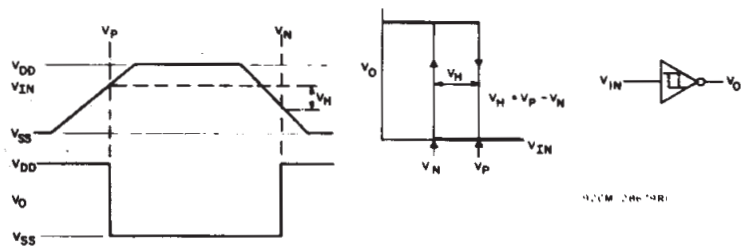


Fig.3 — Minimum output low (sink)
current characteristics.

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STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)								UNITS
	V _O (V)	V _{IN} (V)	V _{DD} (V)	-55	-40	+85	+125	+25				
								Min.	Typ.	Max.		
Quiescent Device Current, I _{DD} Max.	—	0,5	5	1	1	30	30	—	0.02	1	μA	
	—	0,10	10	2	2	60	60	—	0.02	2		
	—	0,15	15	4	4	120	120	—	0.02	4		
	—	0,20	20	20	20	600	600	—	0.04	20		
Positive Trigger Threshold Voltage V _P Min.	—	—	5	2.2	2.2	2.2	2.2	2.2	2.9	—	V	
	—	—	10	4.6	4.6	4.6	4.6	4.6	5.9	—		
	—	—	15	6.8	6.8	6.8	6.8	6.8	8.8	—		
V _P Max.	—	—	5	3.6	3.6	3.6	3.6	—	2.9	3.6	V	
	—	—	10	7.1	7.1	7.1	7.1	—	5.9	7.1		
	—	—	15	10.8	10.8	10.8	10.8	—	8.8	10.8		
Negative Trigger Threshold Voltage V _N Min.	—	—	5	0.9	0.9	0.9	0.9	0.9	1.9	—	V	
	—	—	10	2.5	2.5	2.5	2.5	2.5	3.9	—		
	—	—	15	4	4	4	4	4	5.8	—		
V _N Max.	—	—	5	2.8	2.8	2.8	2.8	—	1.9	2.8	V	
	—	—	10	5.2	5.2	5.2	5.2	—	3.9	5.2		
	—	—	15	7.4	7.4	7.4	7.4	—	5.8	7.4		
Hysteresis Voltage V _H Min.	—	—	5	0.3	0.3	0.3	0.3	0.3	0.9	—	V	
	—	—	10	1.2	1.2	1.2	1.2	1.2	2.3	—		
	—	—	15	1.6	1.6	1.6	1.6	1.6	3.5	—		
V _H Max.	—	—	5	1.6	1.6	1.6	1.6	—	0.9	1.6	V	
	—	—	10	3.4	3.4	3.4	3.4	—	2.3	3.4		
	—	—	15	5	5	5	5	—	3.5	5		
Output Low (Sink) Current, I _{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	—	mA	
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	—		
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	—		
Output High (Source) Current, I _{OH} Min.	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	—	mA	
	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	—		
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	—		
	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	—		
Output Voltage Low-Level, V _{OL} Max.	—	5	5	0.05				—	0	0.05	V	
	—	10	10	0.05				—	0	0.05		
	—	15	15	0.05				—	0	0.05		
Output Voltage High Level, V _{OH} Min.	—	0	5	4.95				4.95	5	—	V	
	—	0	10	9.95				9.95	10	—		
	—	0	15	14.95				14.95	15	—		
Input Current, I _{IN} Max.	—	0,18	18	±0.1	±0.1	±1	±1	—	±10 ⁻⁵	±0.1	μA	



a) Definition of V_P , V_N , V_H

b) Transfer characteristics of 1 of 6 gates

Fig. 6 — Hysteresis definition, characteristics, and test set-up.

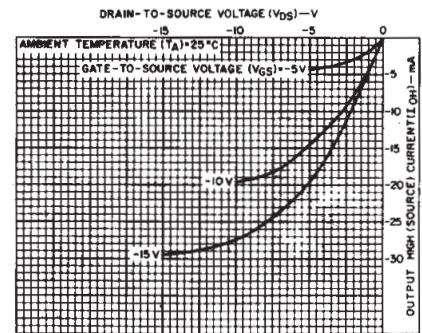


Fig. 4 — Typical output high (source) current characteristics.

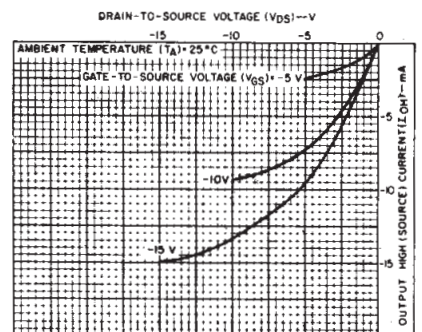


Fig. 5 — Minimum output high (source) current characteristics.

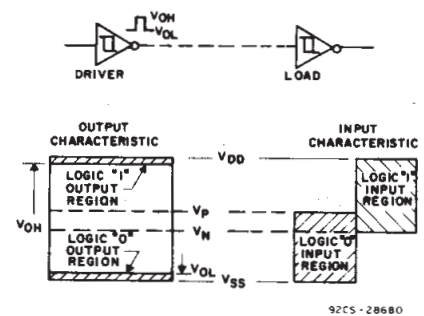


Fig. 7 — Input and output characteristics.

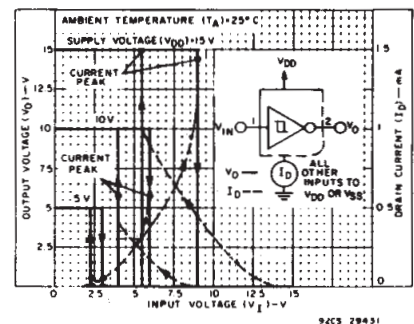


Fig. 8 — Typical current and voltage transfer characteristics.

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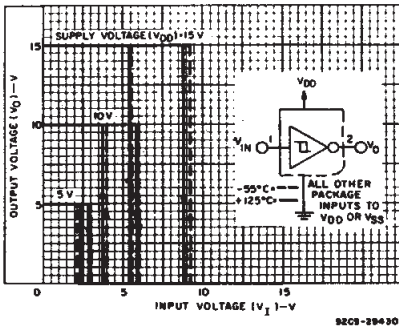


Fig. 9 - Typical voltage transfer characteristics as a function of temperature.

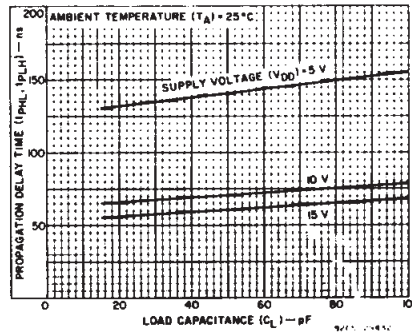


Fig. 10 - Typical propagation delay time as a function of load capacitance.

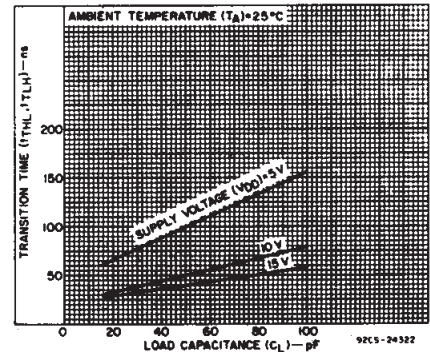


Fig. 11 - Typical transition time as a function of load capacitance.

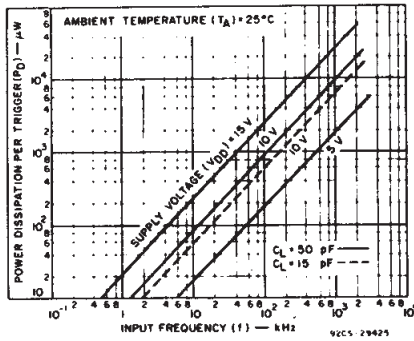


Fig. 12 - Typical power dissipation per trigger as a function of input frequency.

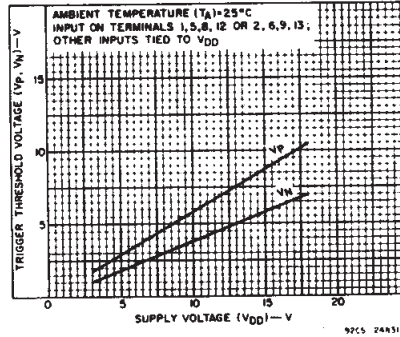


Fig. 13 - Typical trigger threshold voltage as a function of supply voltage.

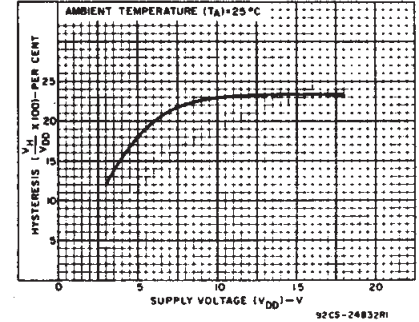


Fig. 14 - Typical per cent hysteresis as a function of supply voltage.

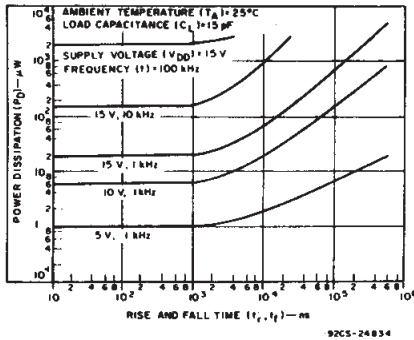


Fig. 15 - Typical power dissipation as a function of rise and fall times.

APPLICATIONS



Fig. 16 - Wave shaper.

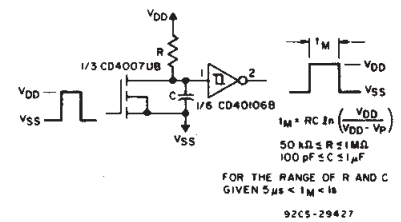


Fig. 17 - Monostable multivibrator.

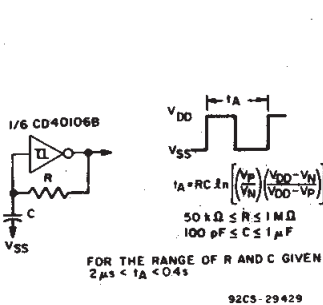


Fig. 18 - Astable multivibrator.

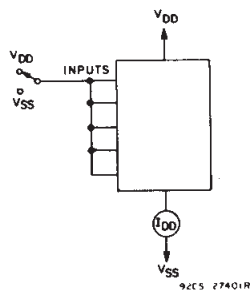


Fig. 19 - Quiescent device current test circuit.

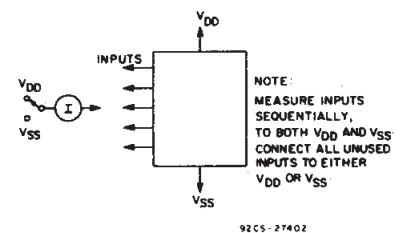


Fig. 20 - Input current test circuit.

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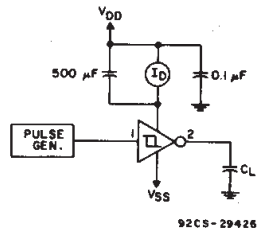
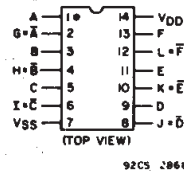
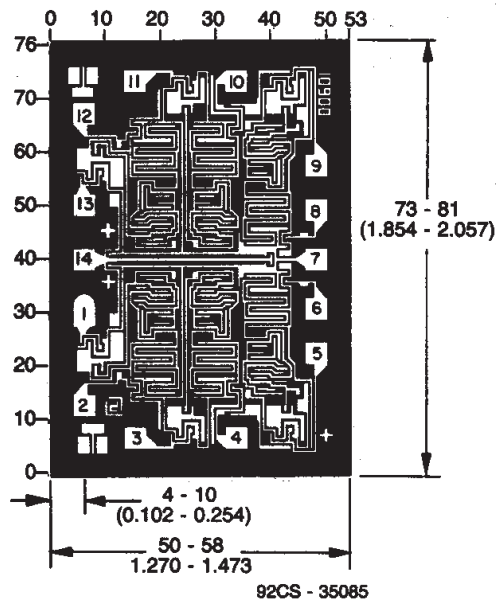


Fig.21 — Dynamic power dissipation test circuit.



TERMINAL ASSIGNMENT



Dimensions and Pad Layout for CD40106BH

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